


<b>Search Notes</b>  	<b>Application/Control No.</b>  10788420	<b>Applicant(s)/Patent Under Reexamination</b>  BRANDWEIN, RICHARD PAUL
	<b>Examiner</b>  Lee, Siu M	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	340, 342, 316, 317	3/16/2007	Siu M. Lee
369	59.18, 53.31	3/16/2007	Siu M. Lee

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	3/16/2007	Siu M. Lee
IEEE	3/15/2007	Siu M. Lee
Discuss application with Cheih Fan	3/15/2007	Siu M. Lee

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner